

Search Notes

Application/Control No.

10/790,134

Examiner

Jean F. Duverne

Applicant(s)/Patent under
Reexamination

CHANG, CHIH-KAI

Art Unit

2839

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 439 | 676 | 4/27/2005 | JFD |
| | 736 | | |
| | 344 | | |
| | 638-639 | | |
| | 76.1 | | |
| | 686 | | |
| | 689 | 4/27/2005 | JFD |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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